

Transverse beam size monitoring at FCC

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with many thanks to U. Iriso, A. Nosych, L. Torino (ALBA), F. Ewald (ESRF), M. Siano (UniMi)

Outline

Requirements for FCC-ee transverse diagnostics

Synchrotron Radiation based techniques

- pinhole camera

- X-ray imaging

- X-ray interferometry

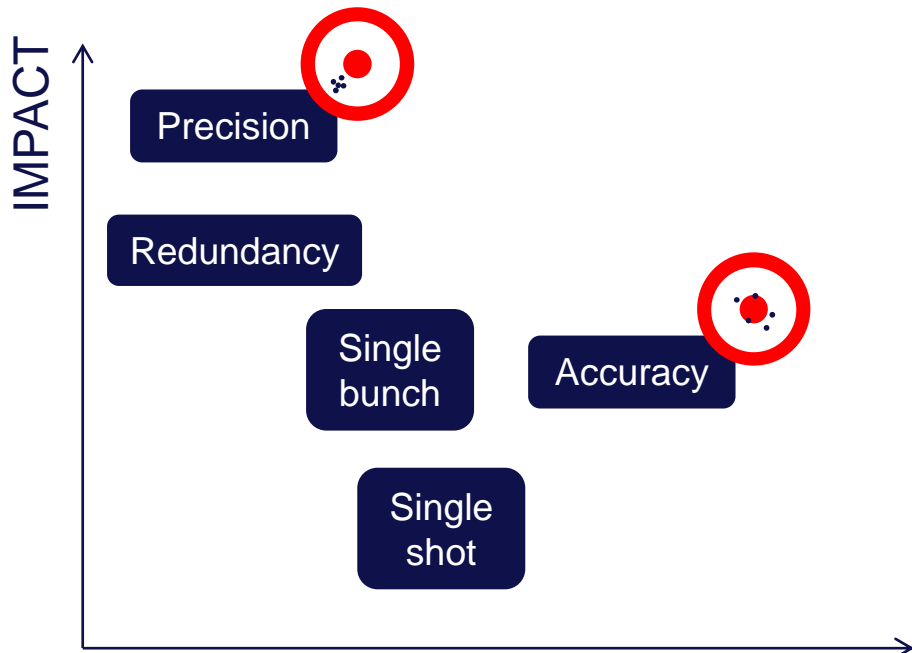
Implementation scenarios

- source options

- extraction lines

Conclusion

Requirements for transverse diagnostics



Qualitative priority matrix based on present understanding of needs

Real-time precise measurement is top priority for commissioning

On-demand accurate measurements required for machine optimization

Multiple systems likely required to meet all specifications

[BI specs input spreadsheet](#)

Pinhole camera



$$\sigma_{beam}^2 = f(\sigma_{light}^2) - \sigma_{resolution}^2$$

Standard for X-ray diagnostics

- **robust** and minimal system
- good **precision** $< 2\%$
- good **accuracy** for $\sigma > 50 \mu\text{m}$
- possible **bunch-by-bunch**
- typically $E_{ph} < 100 \text{ keV}$

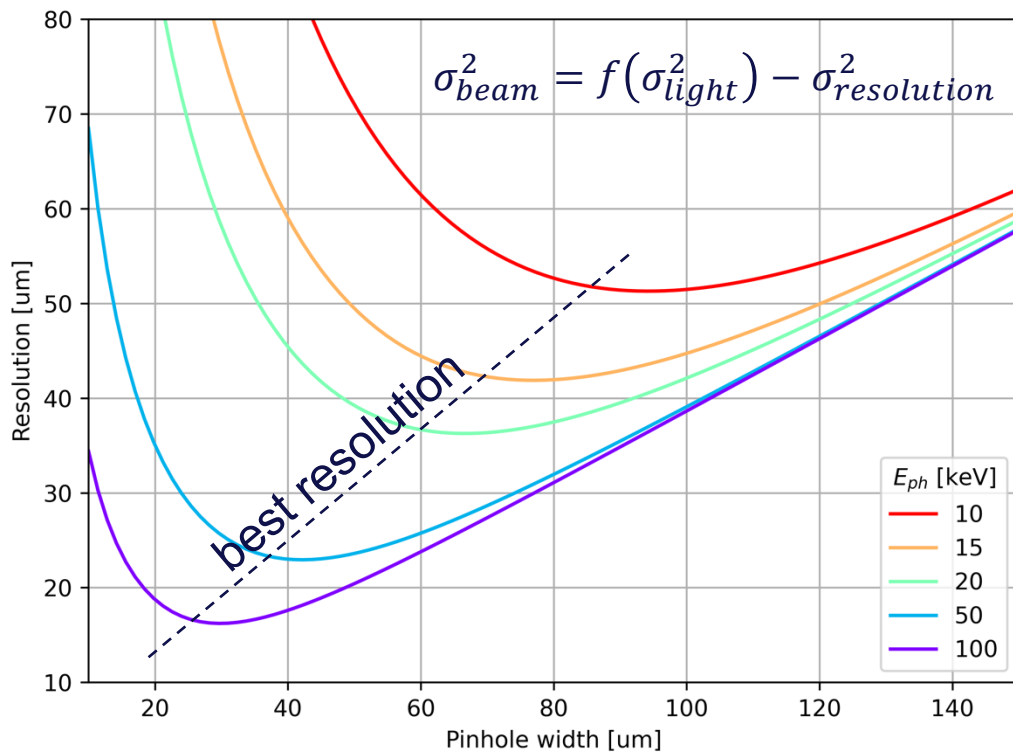
Parameters for FCC

- $d \sim 100 \text{ m}$ for beam-light separation
- $D/d \sim 3 - 4$ for magnification
- w_{PH} to maximize resolution, but $> 10 \mu\text{m}$ for manufacturing

Resolution of pinhole camera

Ultimate resolution of SR diagnostics is diffraction limit

$$\sigma_{resolution} \xrightarrow{\text{diff lim}} \frac{\lambda}{4\pi\vartheta_{SR}} \approx^* 0.2 \mu\text{m}$$



Pinhole camera resolution determined by pinhole width

→ accurate for $\sigma_{beam} \geq 50 \mu\text{m}$

Measurements of smaller beam sizes limited by resolution

*realistic 50 keV photons and $\vartheta_{SR} \approx 0.1\rho^{1/3}\lambda^{2/3} \approx 10 \mu\text{rad}$

X-ray imaging

Upgrade pinhole camera adding X-ray optics

$$\sigma_{\text{resolution}} \xrightarrow{\text{diff lim}} \frac{\lambda}{4\pi\vartheta_{SR}} \approx 0.2 \mu\text{m}$$



Stack of
Compound Refractive Lenses



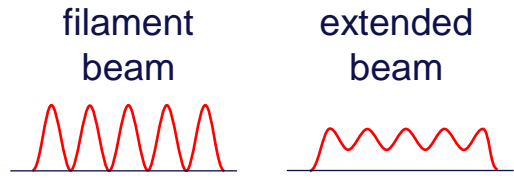
Pair of Kirkpatrick-Baez
focusing mirrors

...allow better resolution but **come with drawbacks**

- suffer from chromatic aberrations
- non-negligible attenuation
- increased setup complexity

X-ray interferometry

Interferometry is complementary technique to imaging
 → **assess beam size from contrast** of interference fringes



Variety of targets

- apertures/slits
- scattering fibers
- nanostructured materials

better resolution than pinhole...



...but with common **challenges**

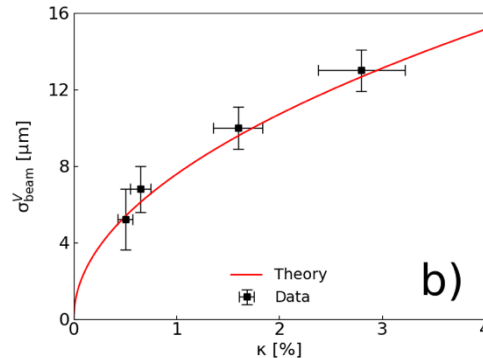
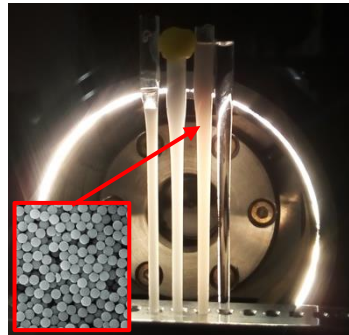
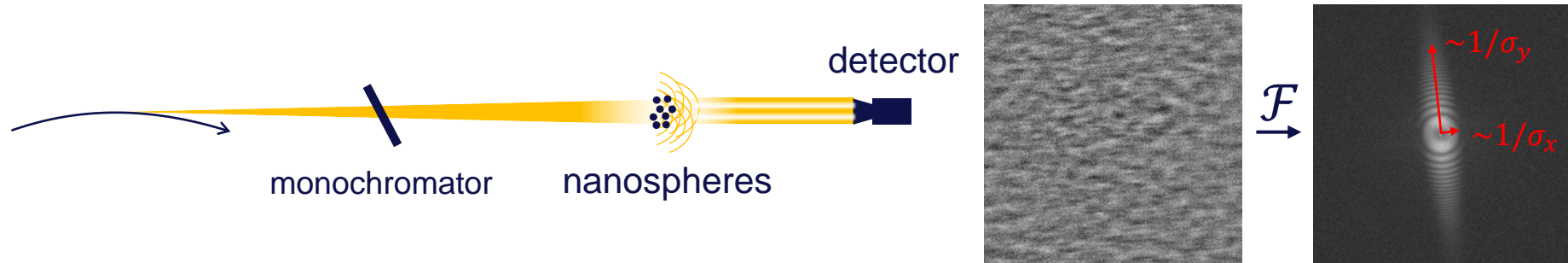
- require monochromatic light
- highly sensitive to distortions
- increased setup complexity

Imaging and interferometry can **coexist** on same extraction line, often with same detector

X-ray Heterodyne Near Field Speckles



Interferometric technique using nanosphere ensemble as interference target



Measurements at ALBA synchrotron (Spain)

- systematic validation at undulator beamline
- measured beam size as small as 4.5 μm

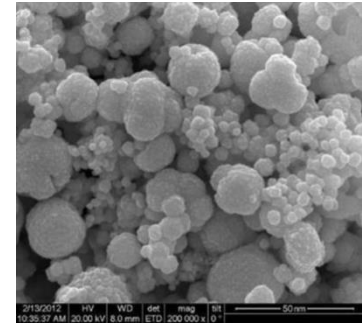
X-ray Heterodyne Near Field Speckles



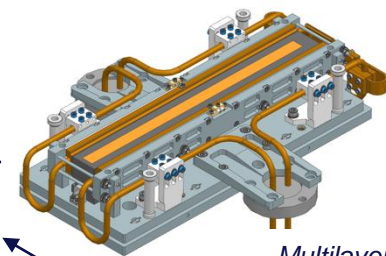
Challenges to deploy technique at FCC-ee

- high energy photons
- broadband (dipole) SR source

→ dedicated R&D studies to develop, characterize and test **target and setup** compatible with FCC environment



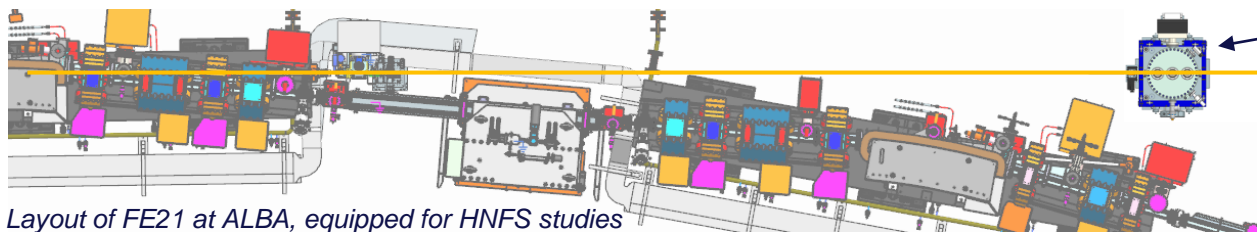
Nanostructured gold target



Multilayer monochromator

Movable target

Detector



Layout of FE21 at ALBA, equipped for HNFS studies

Implementation scenarios

Diagnostic challenges

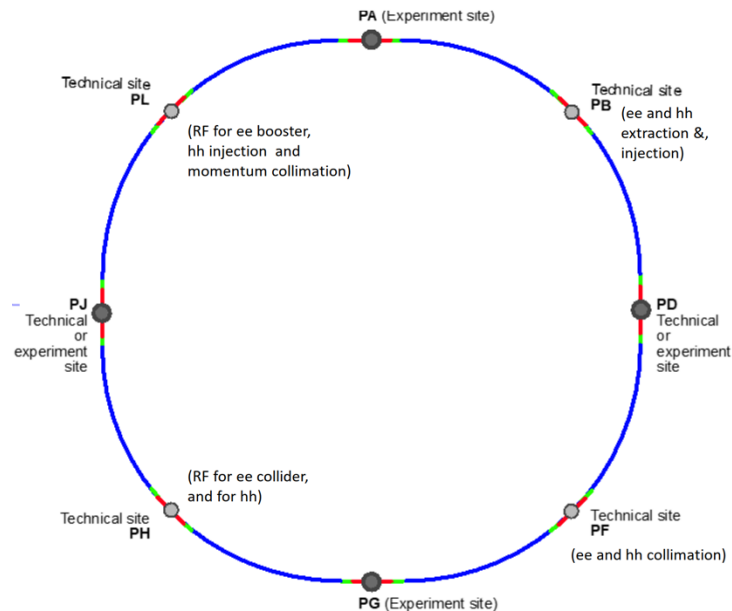
- small vertical beam sizes
- high photon energy

Integration challenges

- high radiation and power load
- large bending radius (long extraction lines)

Options for SR source

- **arc dipole**: maximum flexibility but harsh environmental conditions
- **exp/tech site dipoles**: limited choice but more favorable beam sizes



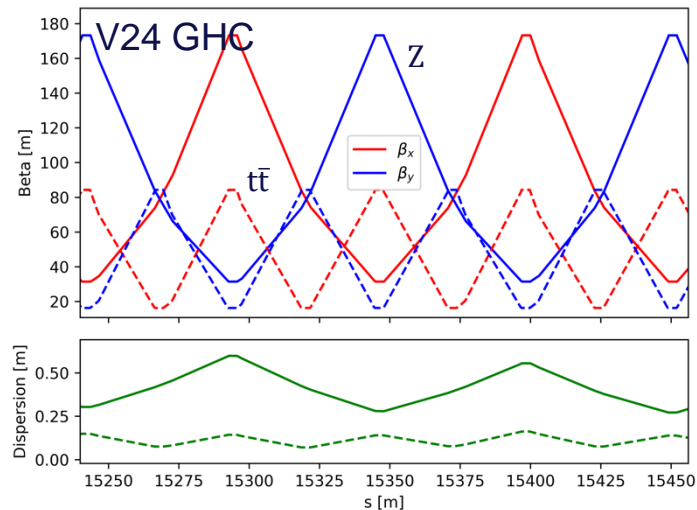
Arc dipoles

Parameter	Z	WW	ZH	ttbar	Unit
Energy	45.6	80	120	182.5	GeV
Current	1283	135	26.8	5.0	mA
Emittance H / V	700 / 1.9	2160 / 2.0	660 / 1.0	1510 / 1.36	pm
ρ / l arc dipole			10000 / ~20		m
λ_c / E_c arc dipole	59.0 / 21.0	10.9 / 113.6	3.2 / 383	0.9 / 1350	pm / keV

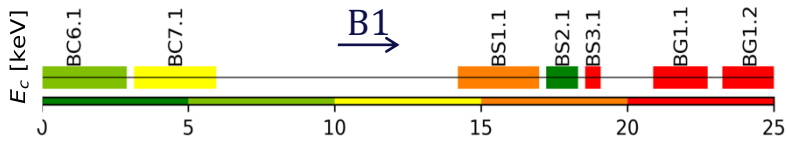
- **radiation power load** ~8kW/mrad
- **photon energy** beyond diagnostics capabilities and destructive for instrumentation in ttbar
- **challenging beam sizes** due to low beta in arcs

Z { $\beta_y \sim \beta_x \sim 100$ m
 $\epsilon_{(y)} \sim 1.9$ pm
 $\sigma_{\min}(y) \sim 14$ μ m

ttbar { $\beta_y \sim \beta_x \sim 50$ m
 $\epsilon_{(y)} \sim 1.4$ pm
 $\sigma_{\min}(y) \sim 8$ μ m

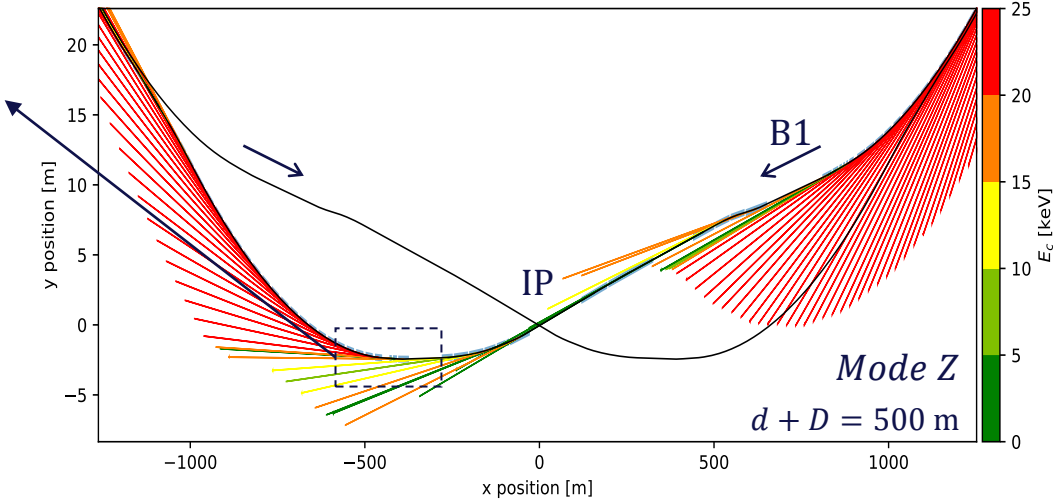
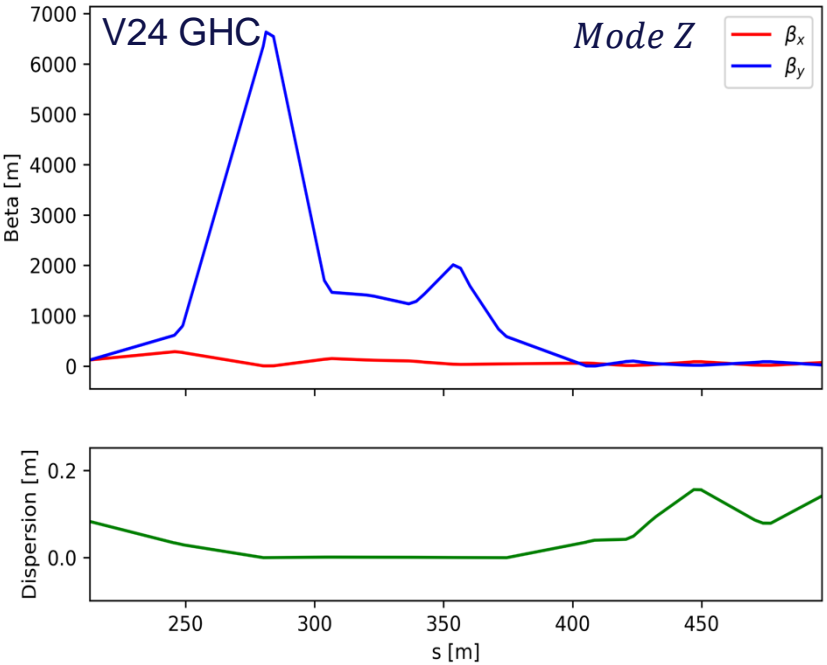


Magnet downstream of Interaction Points



Profit from larger beam size to insert dedicated magnet and provide diagnostics near the IPs, using arcs for light separation

$\beta_y \sim 1000$ m with $\sigma_{res} \sim 35$ μm for pinhole at $E_c = 20$ keV
 $\sigma_y \sim 45$ μm

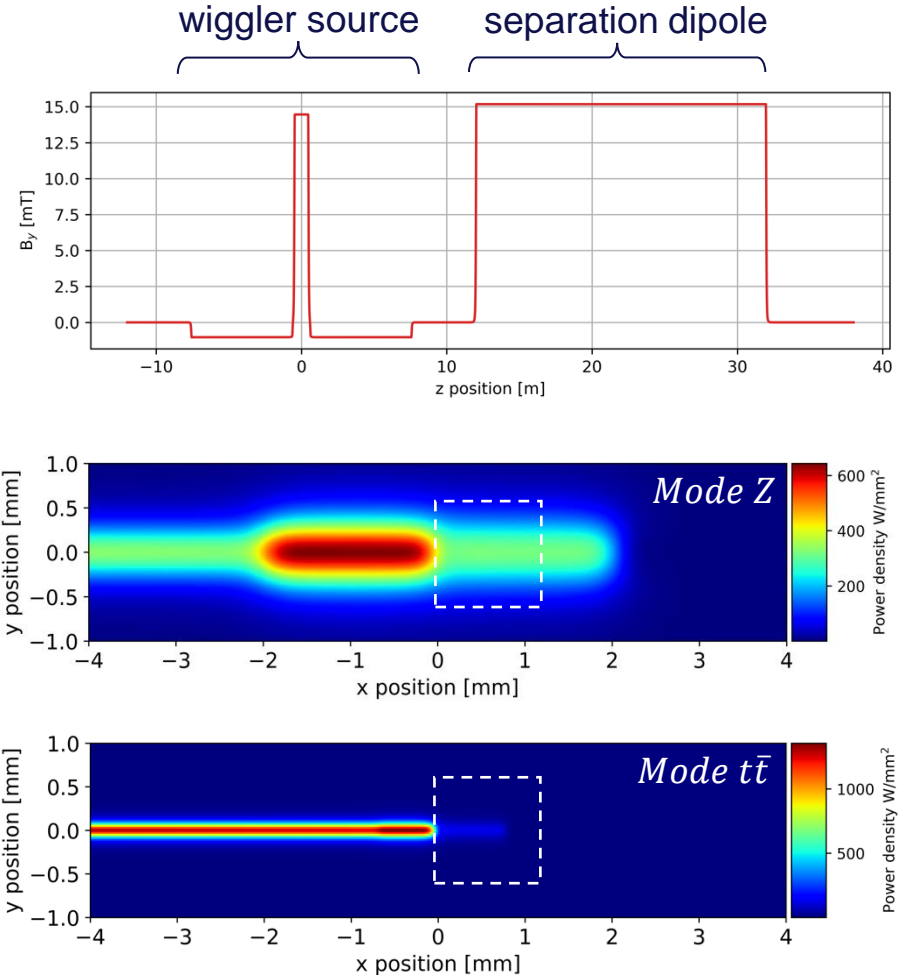


Synchrotron radiation source

Wishlist

- photon energy in range $E_{ph} \sim 20 \div 80$ keV
- within an angle ~ 10 μ rad (1 mm @ 100 m)
- location with **beam size** > 40 μ m in both directions for accurate measurements
- locations w/ and w/o dispersion for **momentum spread evaluation**
- **upstream of strong bends** (e.g. arcs) to separate as quick as possible
- **tunable with energy** to be as constant as possible throughout operation modes

Work in progress...



Extraction lines

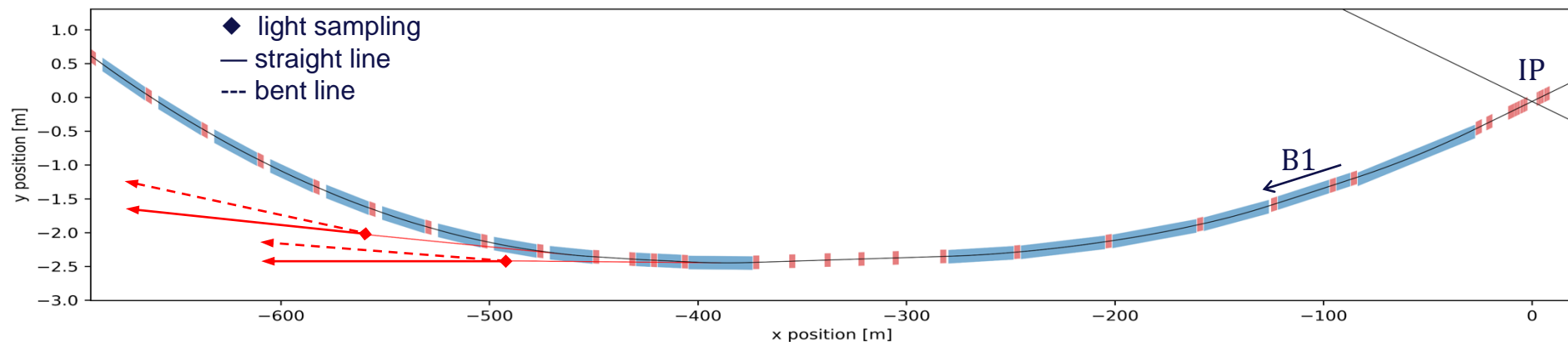
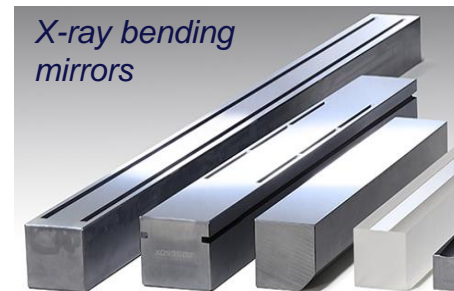
Irrespective of the technique, **long extraction lines required** to separate photons from beam

Straight line option

- ☺ pinhole is straightforward
- ☹ higher radiation at detector
- ☹ larger transverse extension

Bent line option

- ☹ additional mirror for pinhole (monochromator for interferometry)
- ☺ dilute radiation load on mirror
- ☺ more compact transversely



Conclusion

Precise and real-time monitoring is priority for commissioning and operation

→ **pinhole camera** baseline for transverse diagnostics

Pinhole alone cannot meet accuracy requirement in vertical direction

→ **X-ray imaging and interferometry** can complement SR-based diagnostics

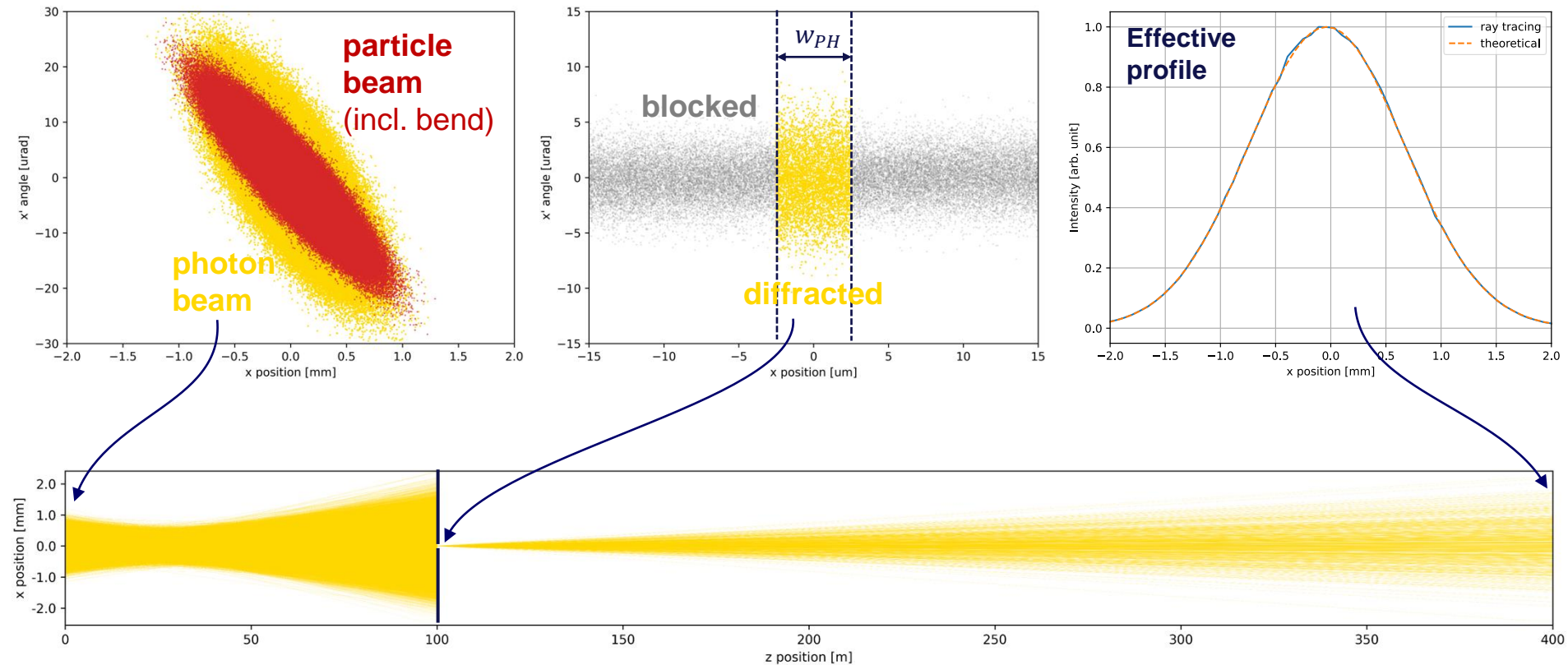
Experimental sites offer more favorable conditions for beam size measurements

→ work in progress on definition of **SR source and extraction line geometry**

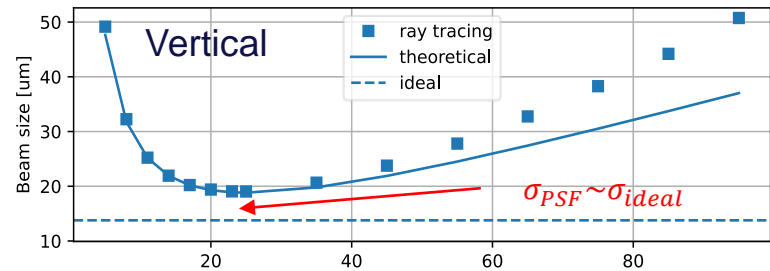


Thank you
for your attention!

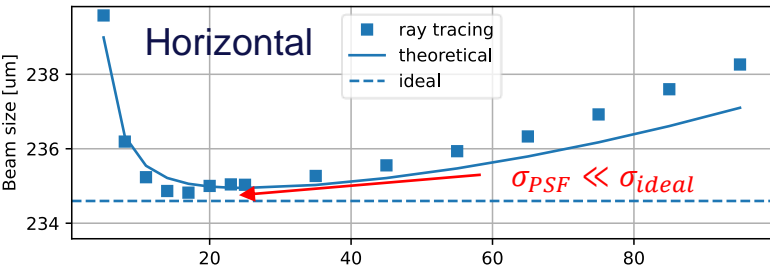
Ray tracing



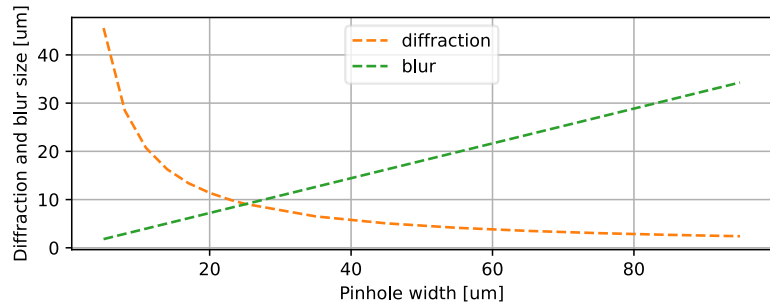
Ray tracing



Ray tracing confirms analytical estimation of the Point Spread Function around the optimum w_{PH}

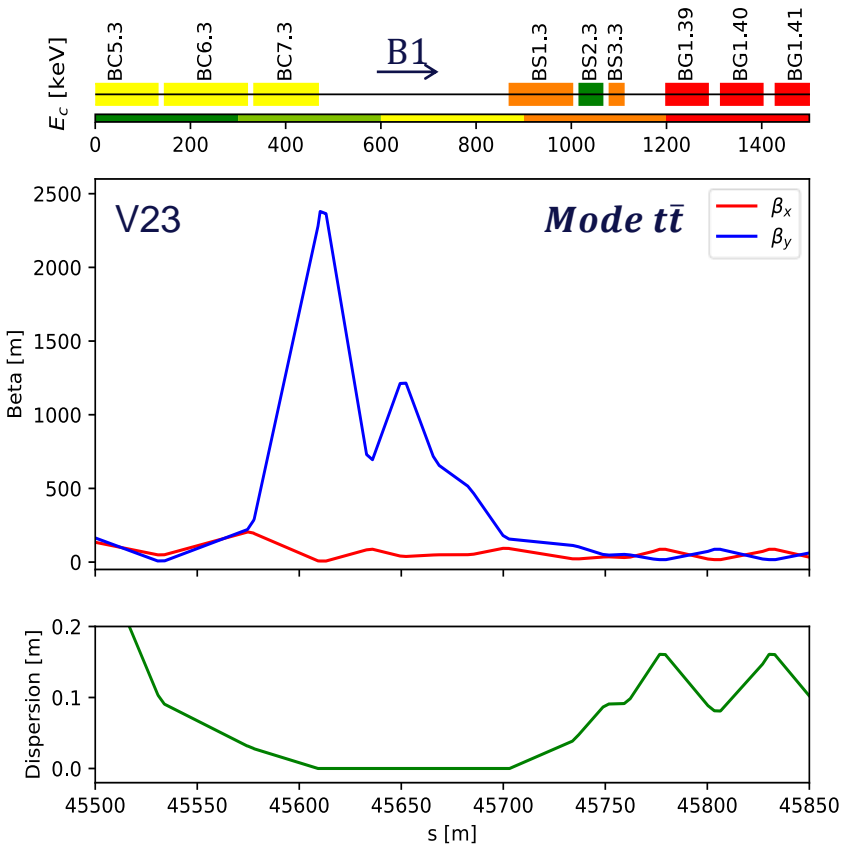


Deviations for large w_{PH} because blur is enhanced by large bending radius



$$\sigma_{eff}^2 = \sigma_{ideal}^2 + \sigma_{PSF}^2$$

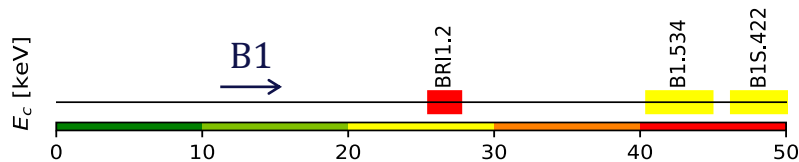
Dipole magnets around IPs (ttbar mode)



Critical energies of most dipoles too high (>1 MeV) for diagnostics at tt mode
 → **working in low frequency tail of spectrum**

Example centre of BC7 😊
 $\beta_y \sim 1500$ m with $\sigma_{PSF}^2 \sim 15 \mu\text{m}$ for pinhole at $E_{ph} = 150$ keV
 $\sigma_y \sim 50 \mu\text{m}$

Dipole magnets around RF



Pro:

- less SR power

Cons:

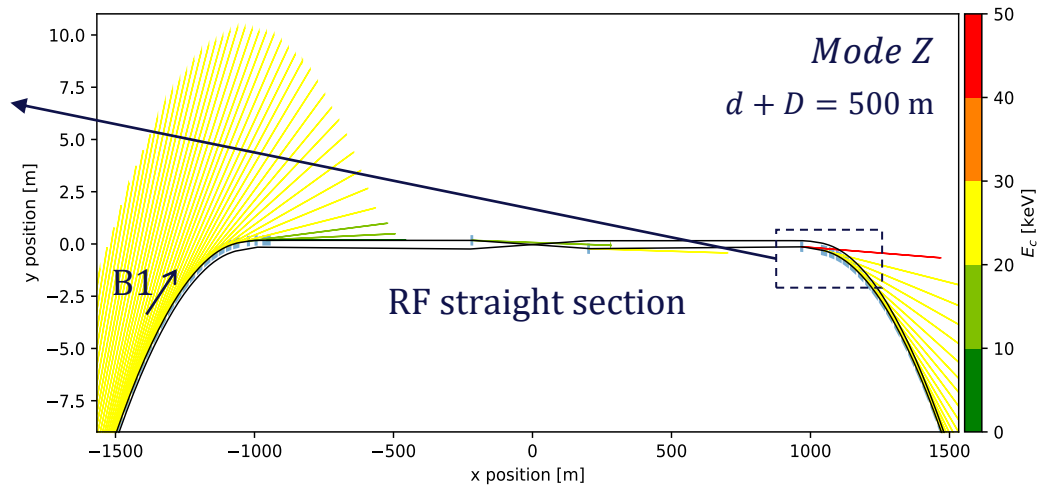
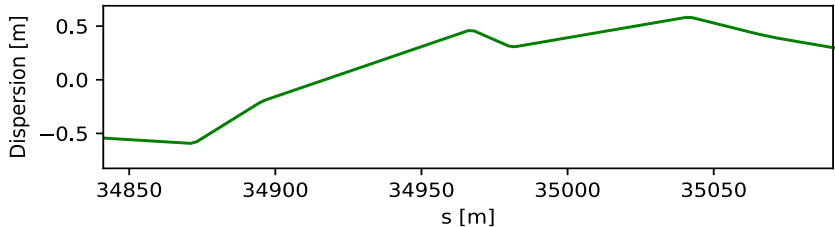
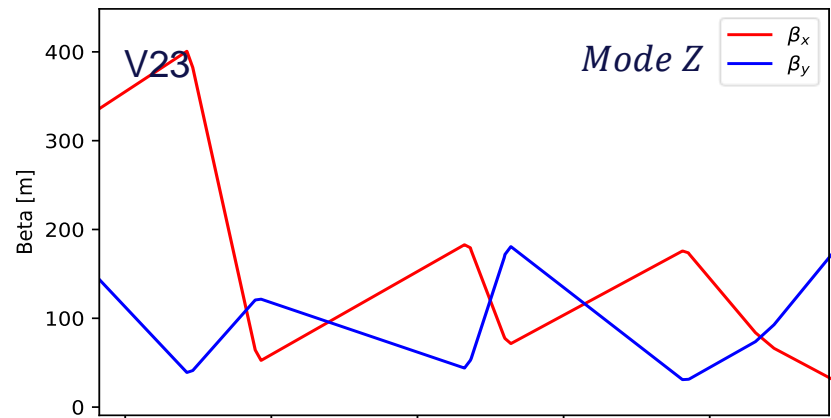
- integration (inside ring and layout changes with mode)
- similar beam sizes as arcs

Example centre of BRI1 ☹️

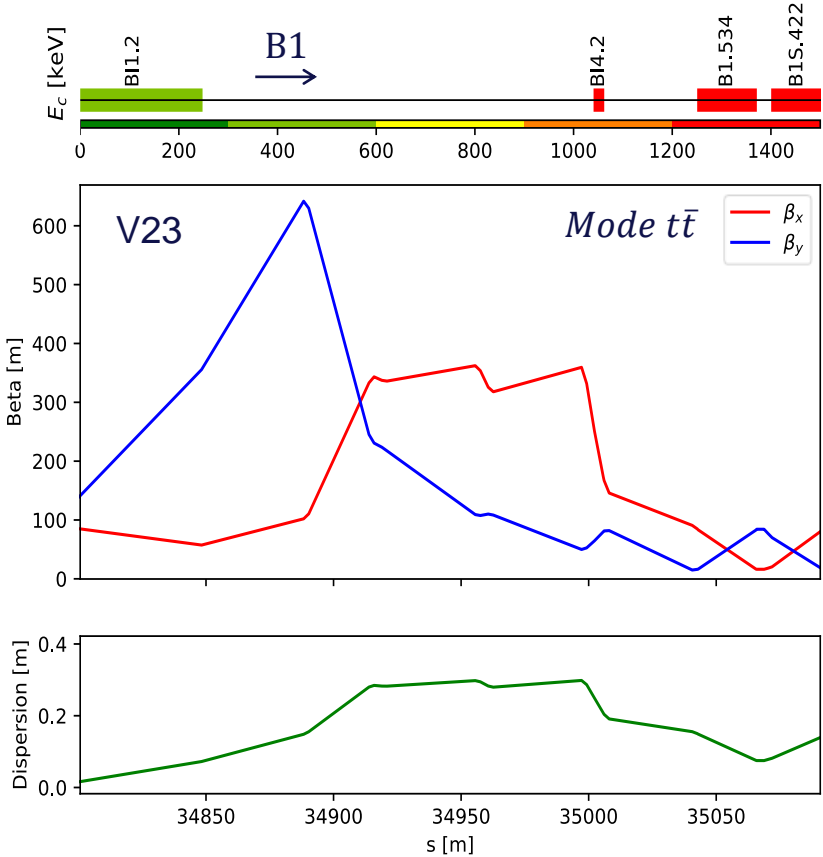
$$\beta_y \sim 100 \text{ m}$$

with $\sigma_{PSF}^2 \sim 25 \text{ } \mu\text{m}^2$ for pinhole at $E_c = 50 \text{ keV}$

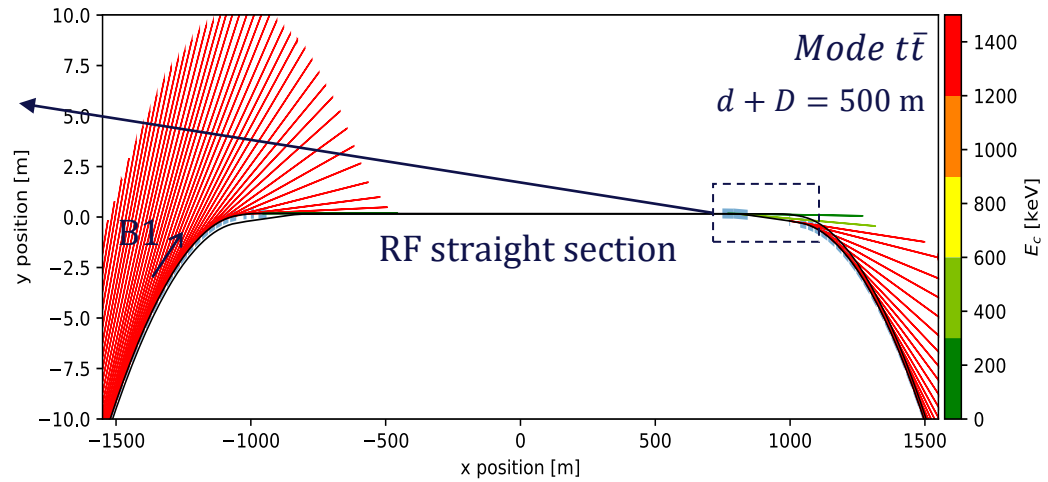
$$\sigma_y \sim 14 \text{ } \mu\text{m}$$



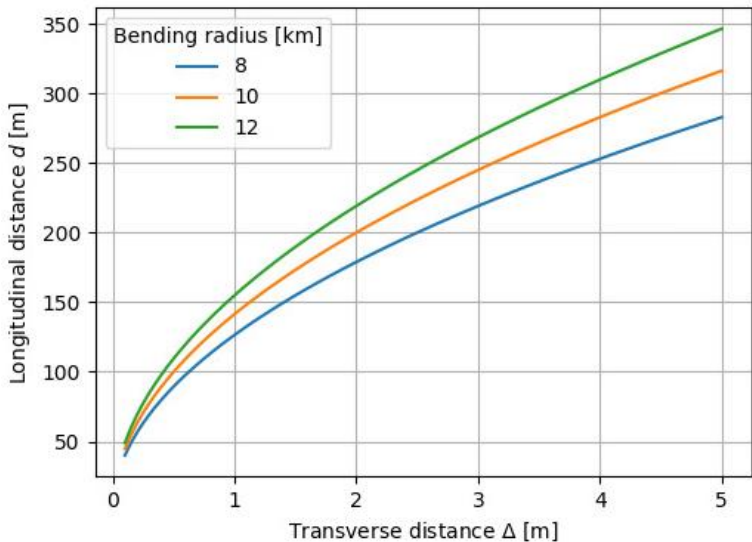
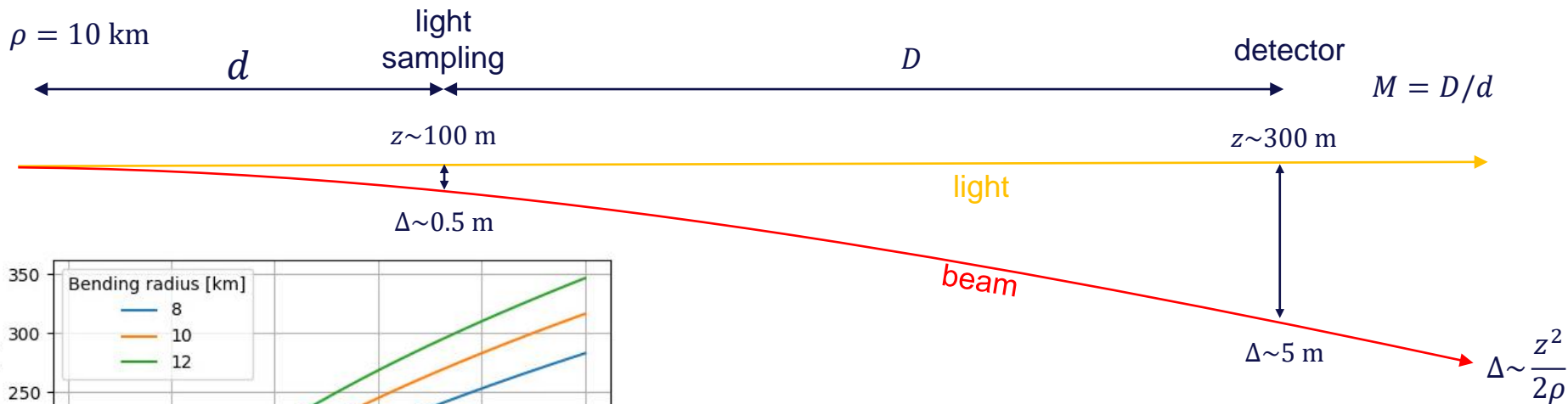
Dipole magnets around RF (ttbar mode)



Example centre of B1 ☹️
 $\beta_y \sim 250$ m with $\sigma_{PSF}^2 \sim 15 \mu\text{m}$ for pinhole at $E_{ph} = 150$ keV
 $\sigma_y \sim 20 \mu\text{m}$



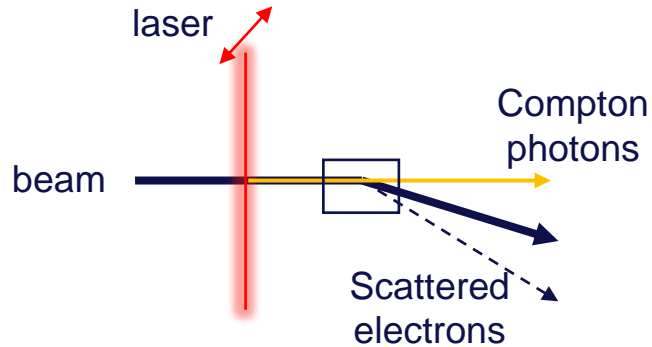
Synchrotron radiation extraction geometry



If we assume to measure **source sizes of 50 μm** , we need at least a factor 2 magnification

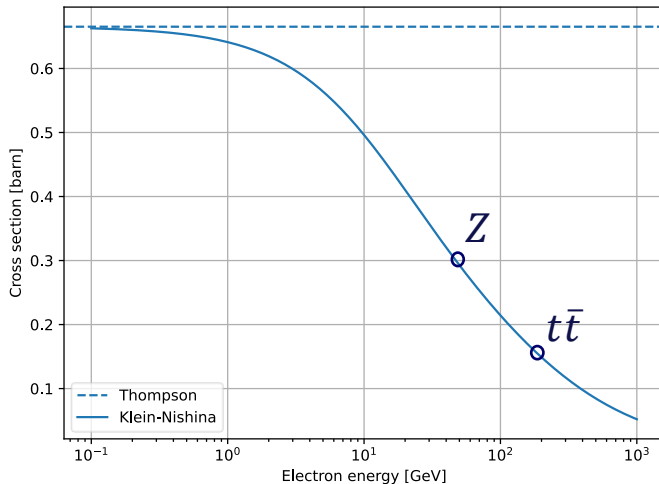
→ requires **$D \sim 200 \text{ m}$** distance from the pinhole, corresponding to **$\Delta \sim 5 \text{ m}$** transverse distance

Alternative to SR diagnostics: Laser Wire Scanner



LWS can achieve micrometric resolution
 → suitable for **accurate vertical measurements**

Similar hardware as **polarimeter**
 → possible common **integration**



FCC has very high electron energies
 → **lower cross section** and **higher photon energy** than all present applications

Laser technology is quickly advancing
 → higher power laser and better focusing systems likely available by FCC era